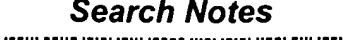


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/873,815	LAVORGNA ET AL.	
	Examiner	Art Unit	
	Tan Dean D. Nguyen	3629	

一

II

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
US	3/06 2/06	DN
Patent PG Pub		
FOREIGN		
1. EPO 2 JPO 3. Derwent		
IBM - TDB	↓	↓

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner